

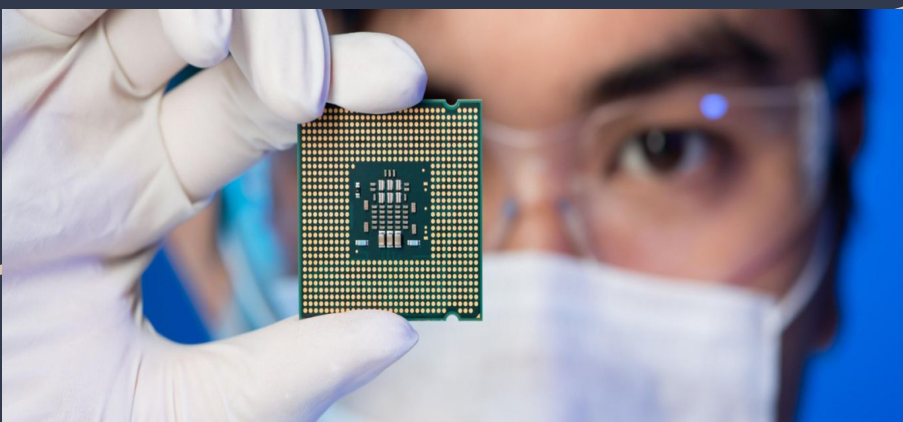
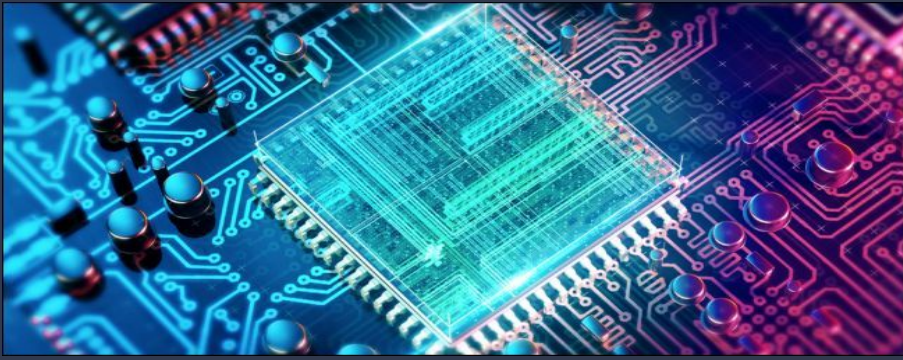
CNTFET

CARBON NANOTUBE FIELD EFFECT TRANSISTOR

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Shravan Kumar (170002047)
Shreyansh Thakur (170002048)

Why CNTFET ?

(Motivation)

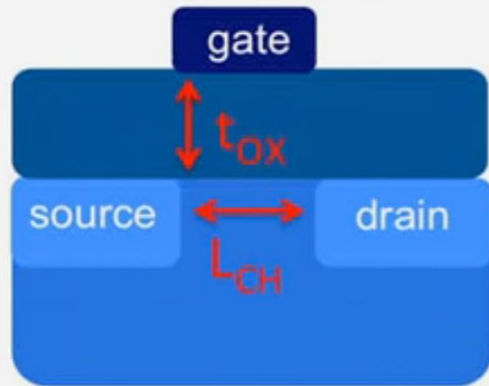


- As the size becomes smaller, scaling the silicon MOSFET becomes harder.
- Requirement of high performance channel material.
- High mobility requirement.
- High leakage Currents. (in MOSFETS)
- Extreme Short Channel Effects.
- High Field Effect.
- High charge mobility in Carbon Nanotubes(CNTs).
- CNTFETs can be scaled to much smaller sizes.

Key Problem:

If t_{ox} gets small (nm), device leaks

But t_{ox} must shrink with device
if not, then gate loses control
of channel



two choices:

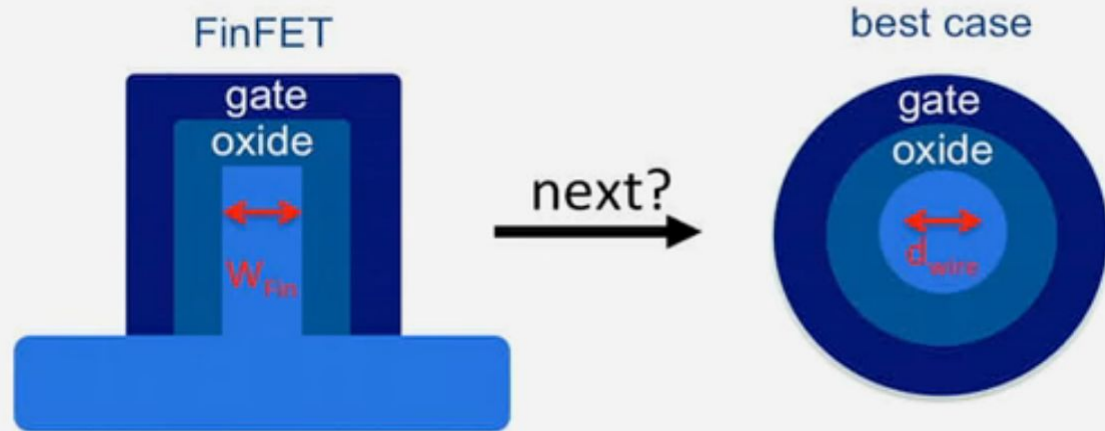
1. change materials
2. change geometry

solution 1: change materials (~ 2006)

$$C_{ox} = \epsilon_0 \kappa \frac{A}{t_{ox}}$$

increase κ by changing the materials: SiO₂ (3.9) to HfO₂ (16)

solution 2: change geometry (~ 2013)

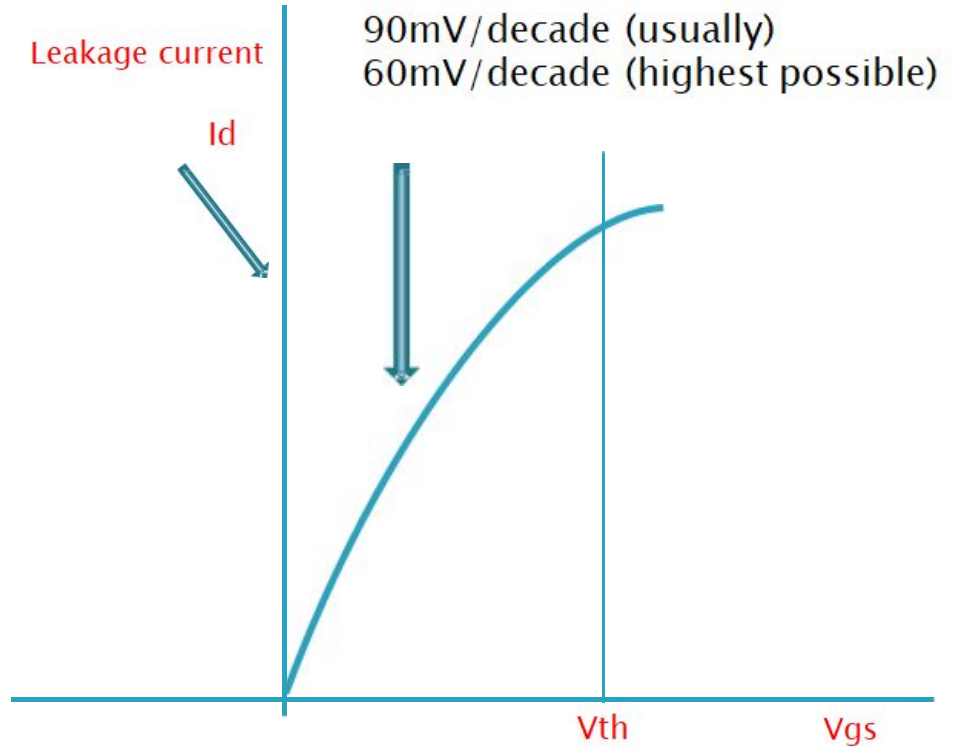


wrapping gate around channel allows better gate control
the thinner the body (W_{Fin}), the smaller the device can be

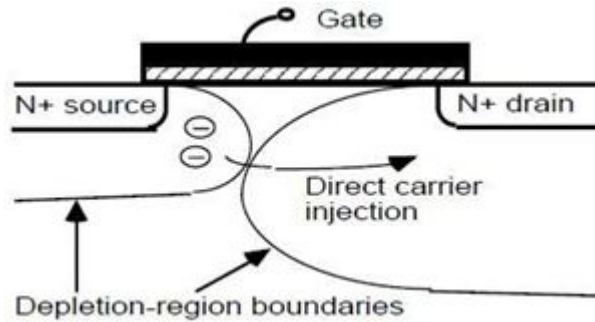
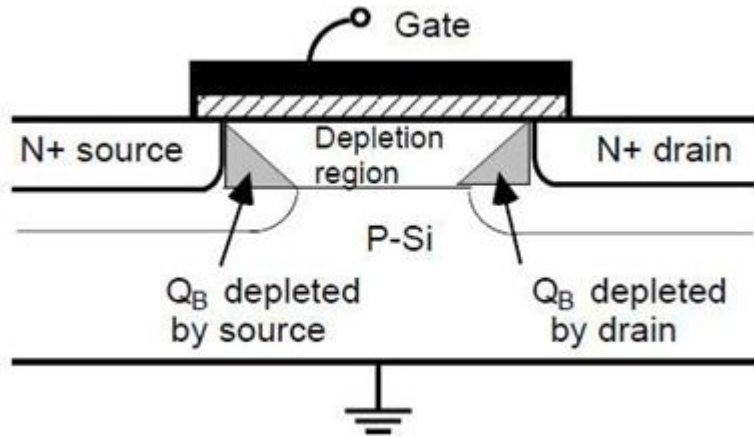
Problems in shrinking the conventional MOSFET

High leakage current

Due to leakage, static power is substantially increased.



Extreme Short Channel Effects

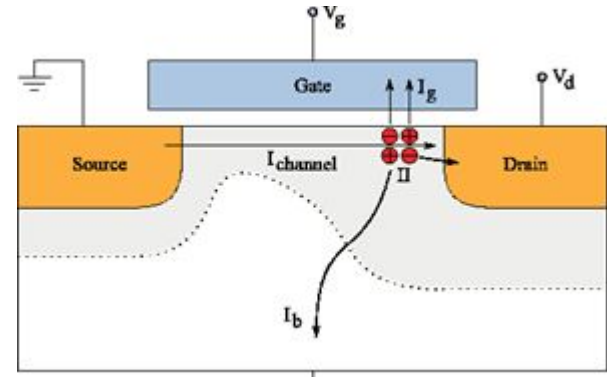


DIBL–Drain Induced
Barrier Lowering
& Punch through

- Extreme Short Channel Effects

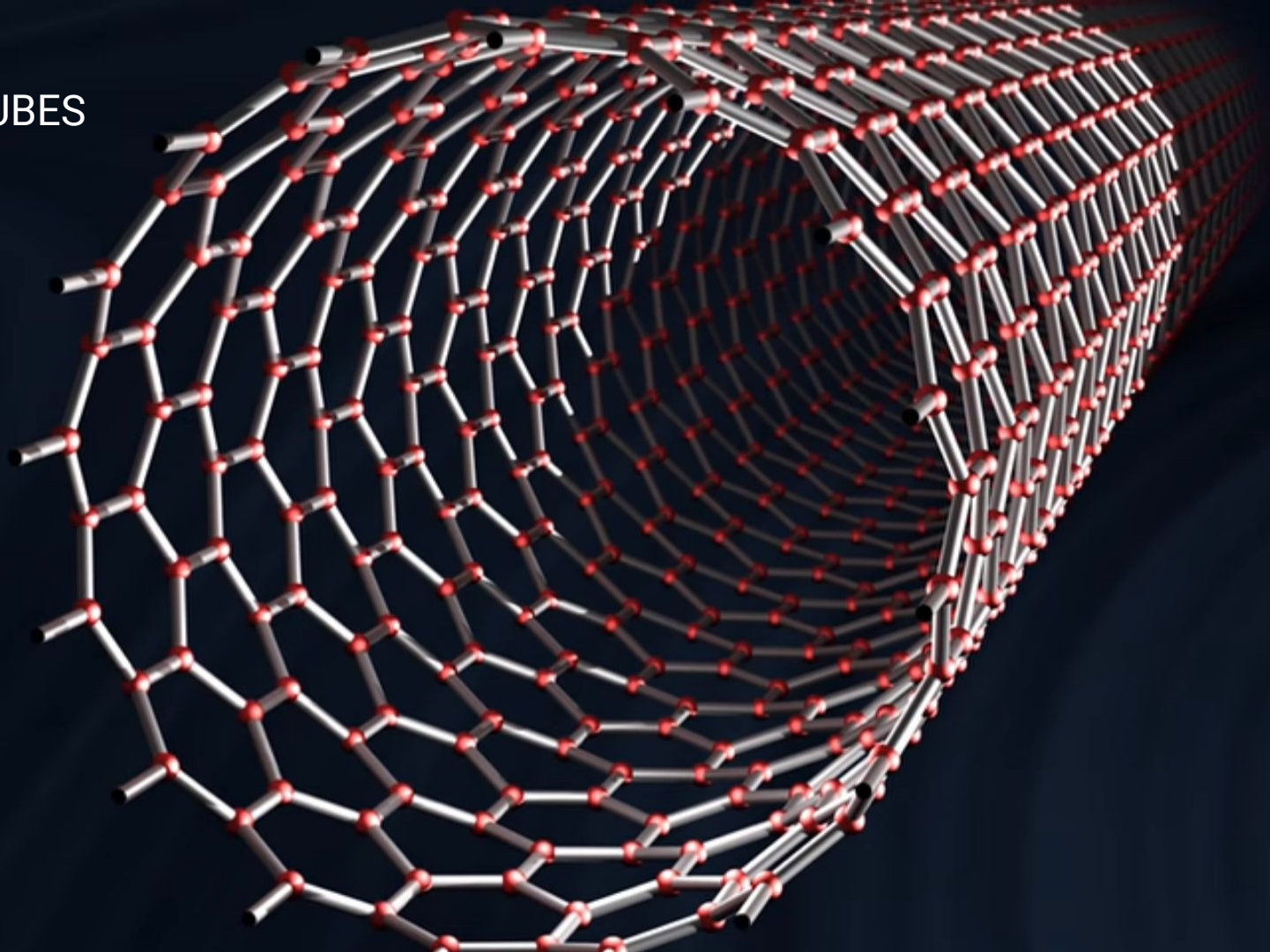
High Field Effects

As size decreases, electric field in channel increases which leads to high kinetic energy of electrons and holes (**hot carriers**) which penetrate into the gate oxide and temper the threshold voltage.



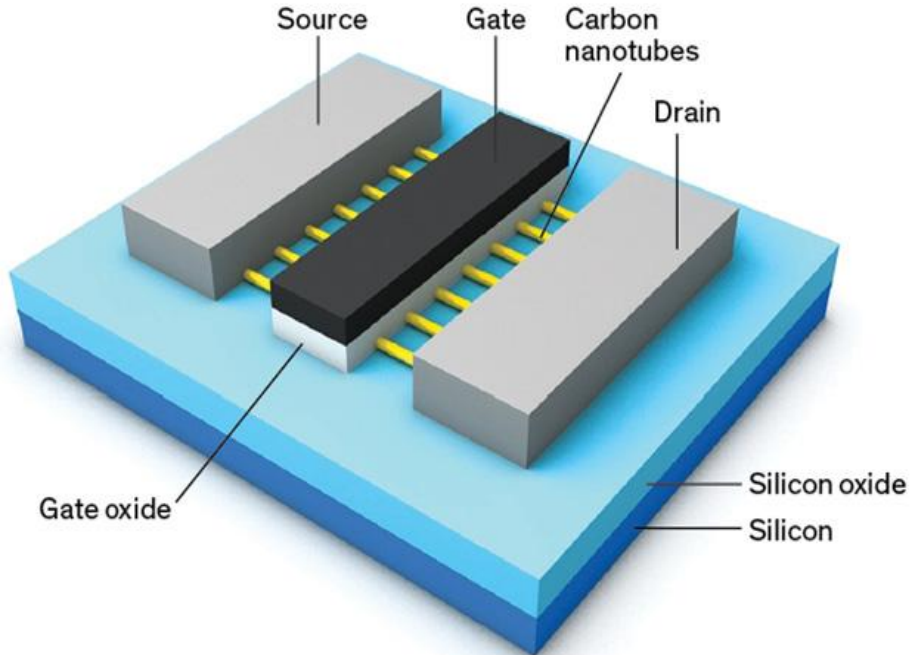
- High Field Effects

CARBON NANOTUBES (CNTs)

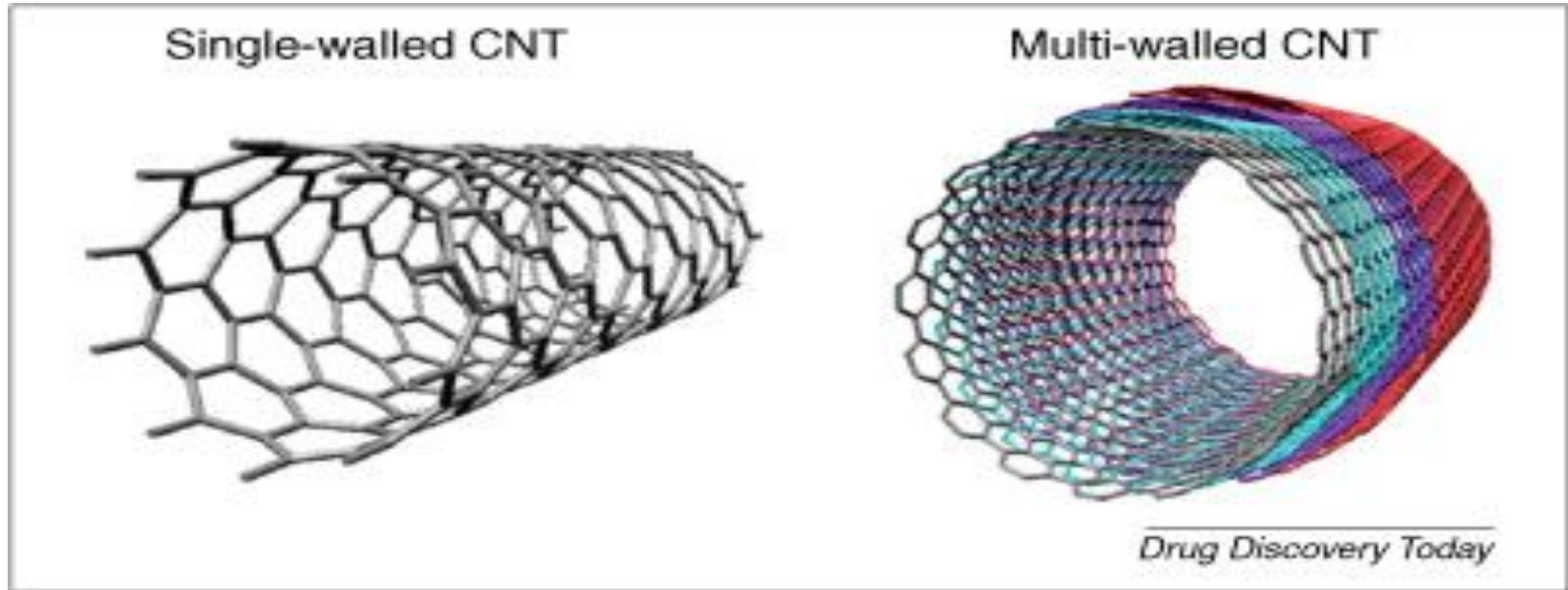


Introduction

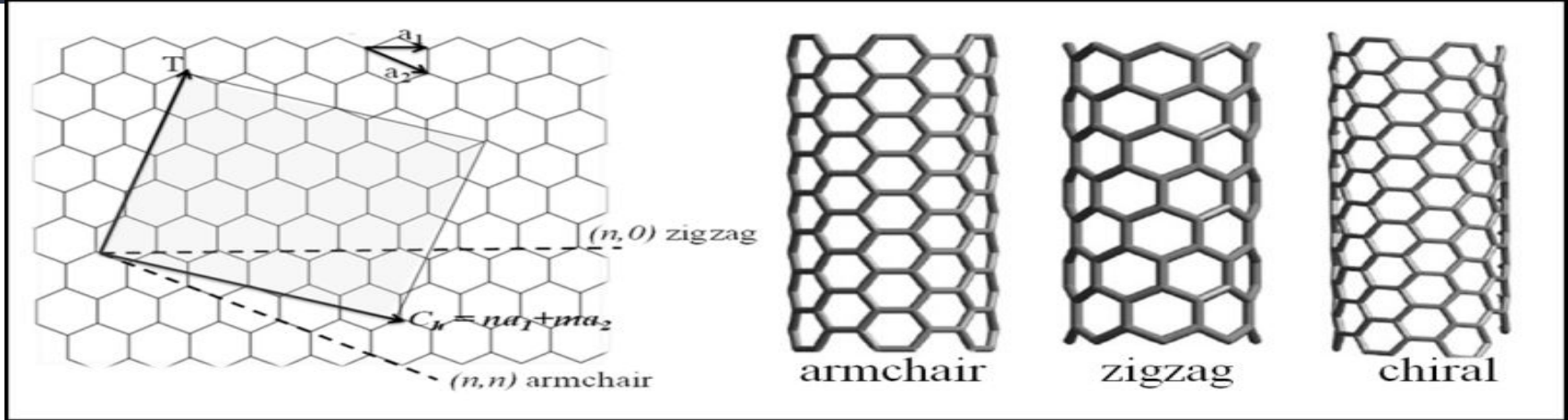
- Carbon Nanotube Field Effect Transistors (**CNTFET**) are promising nano-scaled devices for implementing high performance very dense and low power circuits.
- A Carbon Nanotube Field Effect Transistor refers to a FET that utilizes a single CNT or an array of CNTs as the channel material instead of bulk silicon in the traditional MOSFET structure. The core of a CNTFET is a carbon nanotube.



Carbon nanotubes can be arranged as:



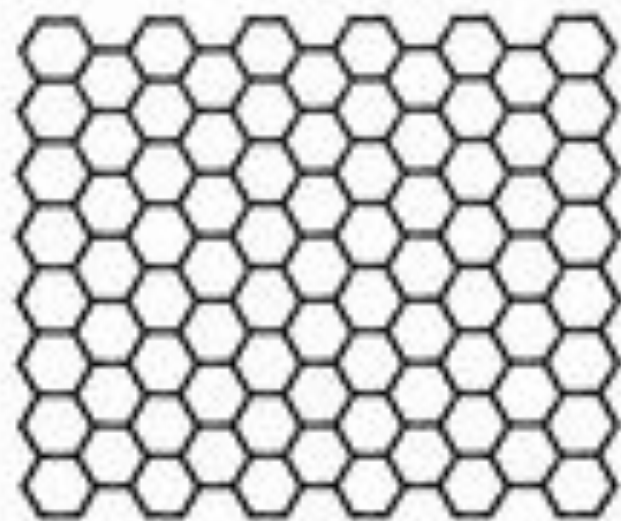
Carbon Nanotubes



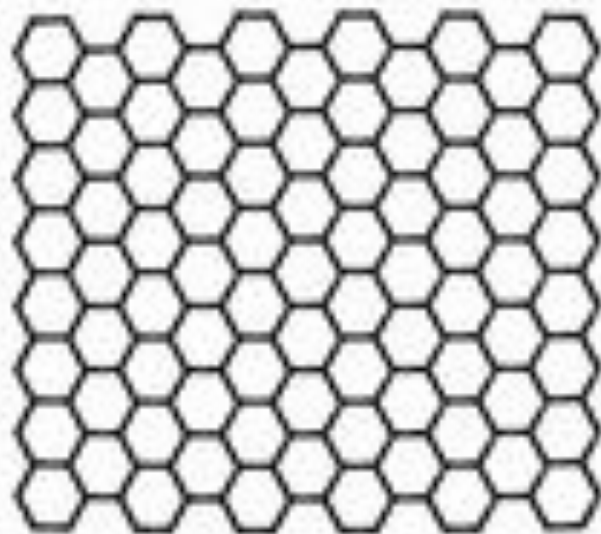
The indices (n_1, n_2) give different properties to the CNT. Accordingly, three types of CNTs can be identified based on way of folding the graphene sheet:

1. Armchair ($n_1 = n_2$)
2. Zig-Zag ($n_1 = 0$ or $n_2 = 0$)
3. Chiral (otherwise).

$$C_h = na_1 + ma_2$$



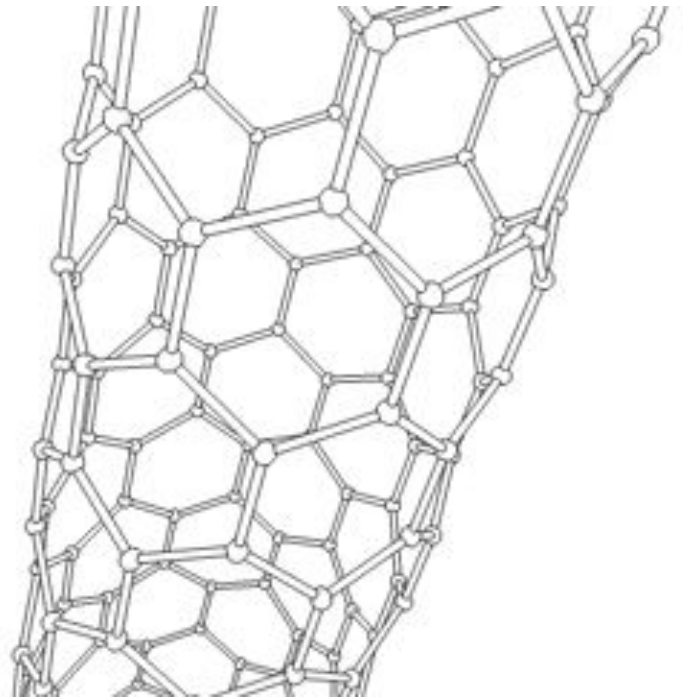
Zigzag SWNT (horizontal roll)



Armchair SWNT (vertical roll)

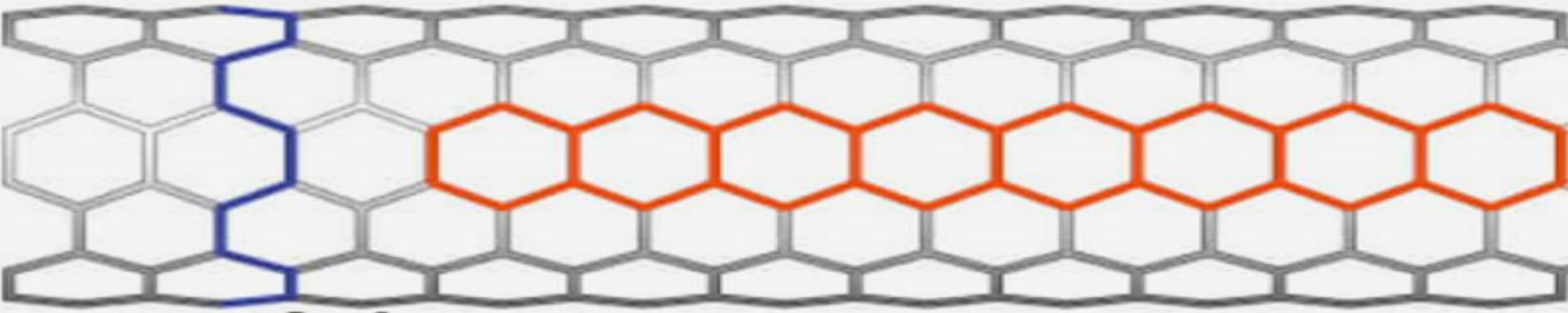
Rotating single-walled zigzag carbon nanotube

One defines a "zigzag" path on a graphene-like lattice as a path that turns 60 degrees, alternating left and right, after stepping through each bond.



Armchair Configuration

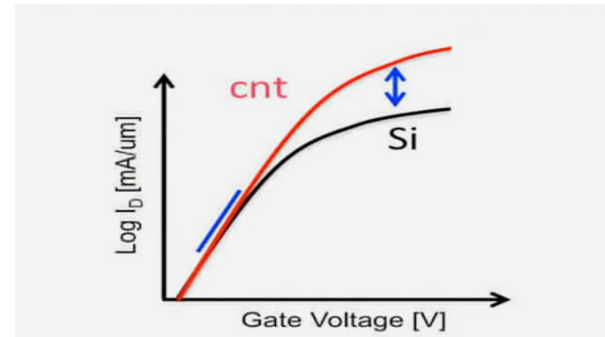
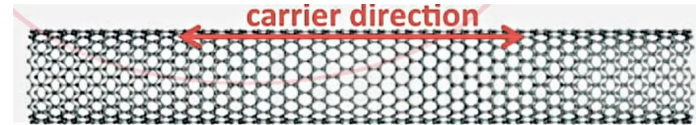
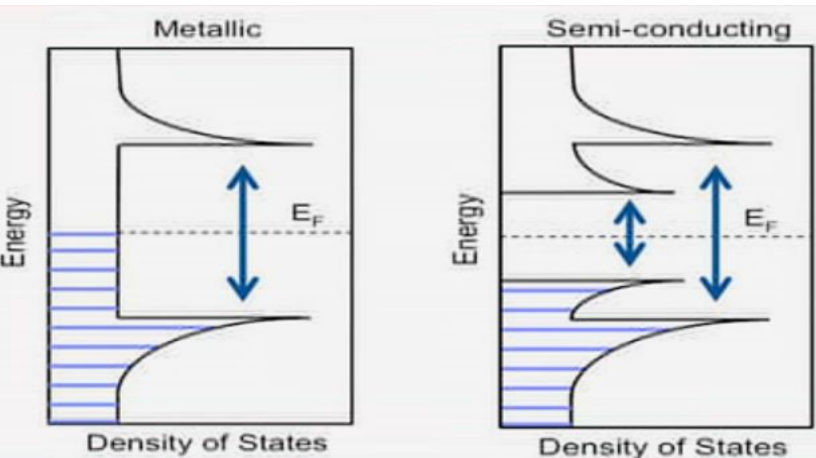
It is also conventional to define an "armchair" path as one that makes two left turns of 60 degrees followed by two right turns every four steps



Theoretical Analysis & Working Principle

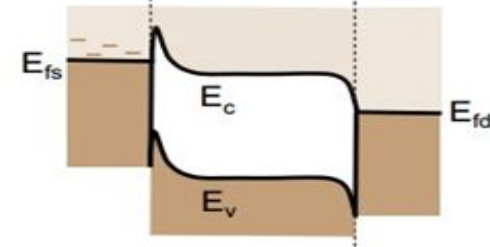
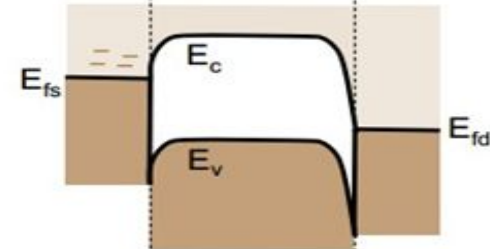
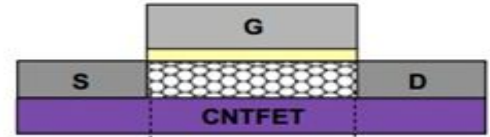
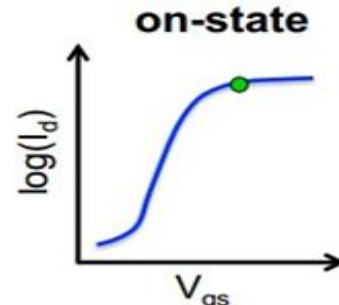
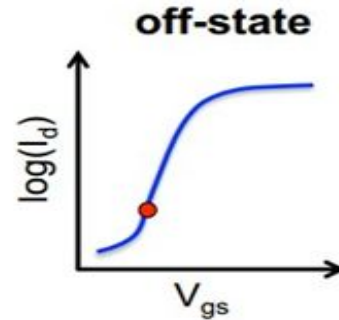
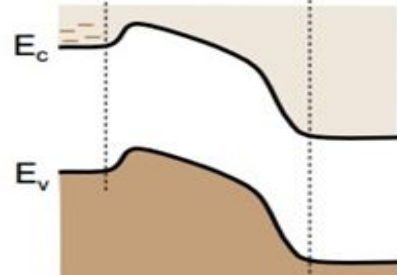
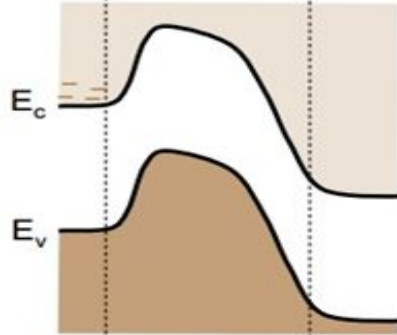
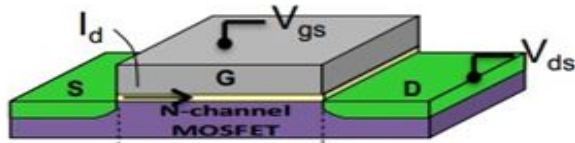
Why Carbon Nanotubes?

- A carbon nanotube band gap is directly affected by its way of folding and diameter. If these properties are controlled, CNTs become a promising candidate for nano-scale FETs.
- Moreover, because of the lack of boundaries in the hollow cylinder structure of CNTs, there is no boundary scattering.



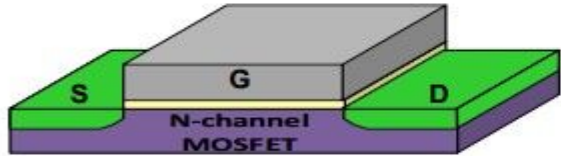
ON and OFF state of CNTFET and MOSFET

- The Gate voltage electrostatically turns the carrier flow in the CNT channel ON or OFF.



Drain Current parameters in CNTFET and MOSFET

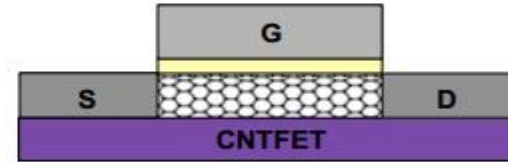
Standard MOSFET



$$I_d = \underbrace{\mu_{eff}}_{\text{carrier mobility}} \underbrace{\frac{W}{L}}_{\text{spatial dependence}} \underbrace{C_{ox}(V_g - V_t)}_{\text{charge in channel}} \underbrace{V_{ds}}_{\text{bias dependence}}$$

- no DOS consideration
- no consideration of contacts

CNTFET



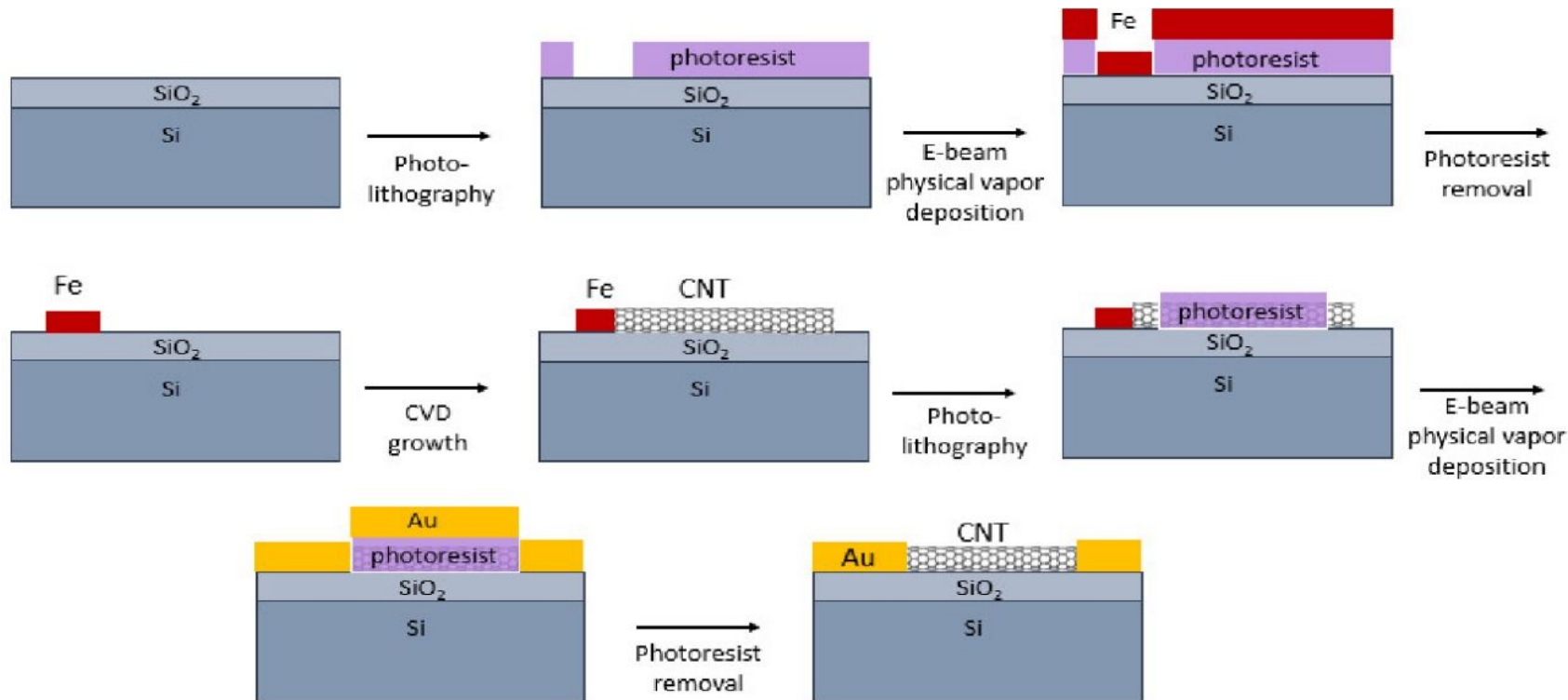
$$I_d = q \underbrace{\int_{E_{fs}}^{E_{fd}} f(E, T) \cdot v(E) \cdot T(E) \cdot D(E) \cdot dE}_{\text{bias dependence (carrier injection determined by states between source/drain Fermi levels)}} \underbrace{v(E)}_{\text{carrier (Fermi) velocity}} \underbrace{T(E)}_{\text{transmission at contacts}} \underbrace{D(E) \cdot dE}_{\text{charge in channel}}$$

- no spatial dependence
- no mobility dependence

Fabrication

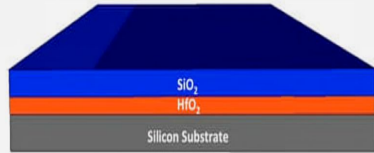
- CNTFETs are of many types, based on the mere placement of the CNTs in several orientations and different designs.
- Many difficult challenges have to be overcome in the fabrication process of CNTFETs, most of which include dealing with CNTs, which, as we know, are extremely small.
- Some of these challenges are discussed later in detail.

Fabrication of Top-Gated CNTFET

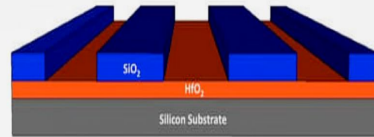


Placement of CNTs during the fabrication process

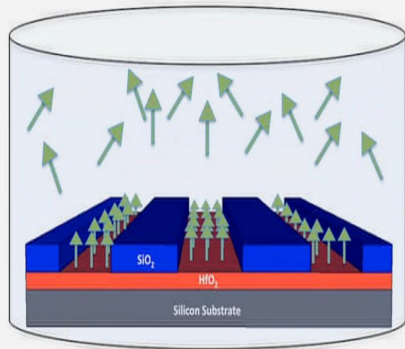
1. grow HfO_2 and SiO_2 on a silicon substrate



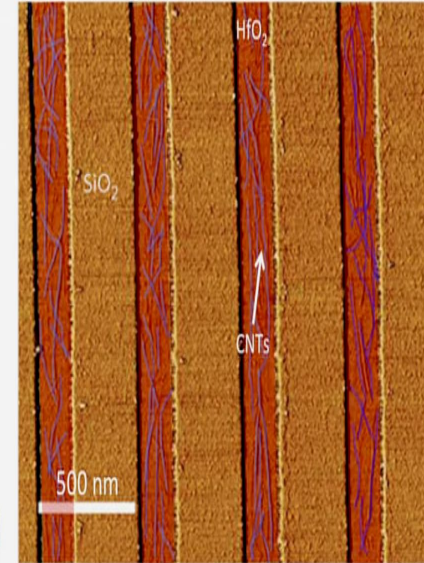
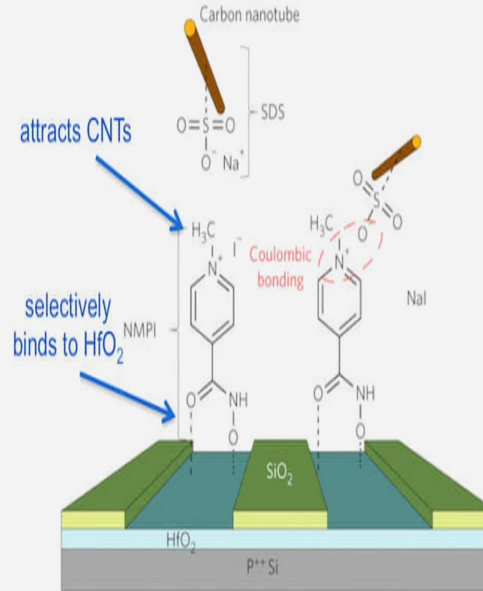
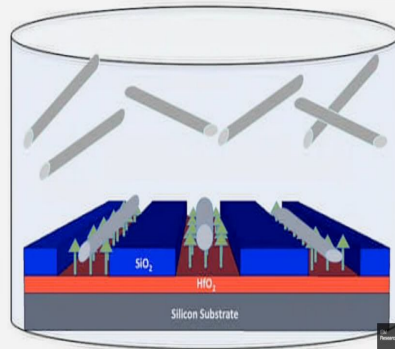
2. pattern into trenches (lithography & etch)



3. place in solution of "selective-glue" molecule



4. place in solution of sorted CNTs



Some "Selective-glues"

Figure of Merits

1

CARRIER TRANSPORT

1-D ballistic transport of carriers leading to high carrier velocities.

2

DEVICE CURRENT

High drive current and large transconductance.

3

STRENGTH

High Temperature Resilience and strong covalent bonds in CNTs.

4

DEVICE SCALING

Scaling to very small channel lengths (~9nm) has been possible till now.

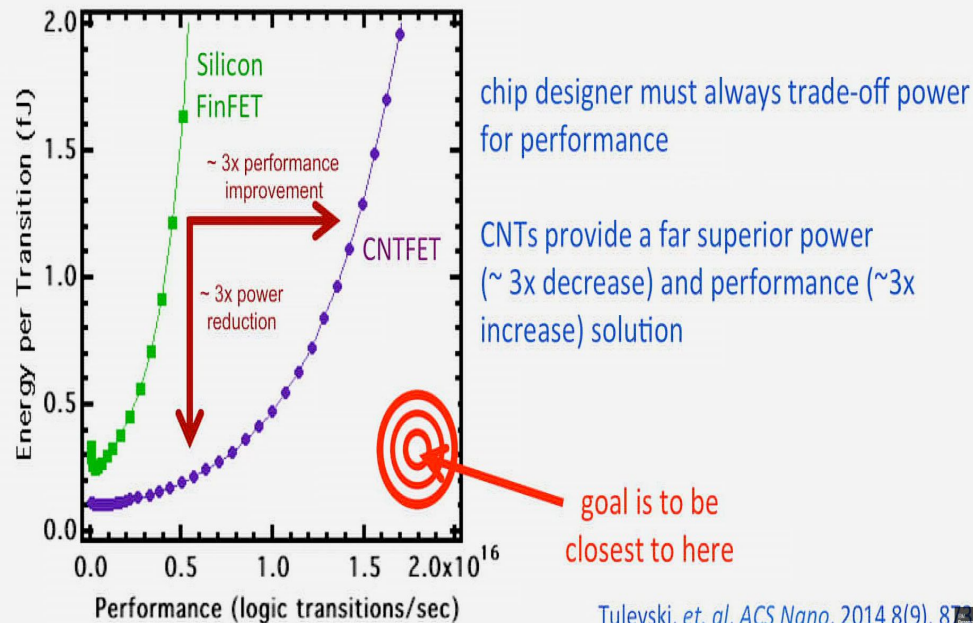
5

PERFORMANCE

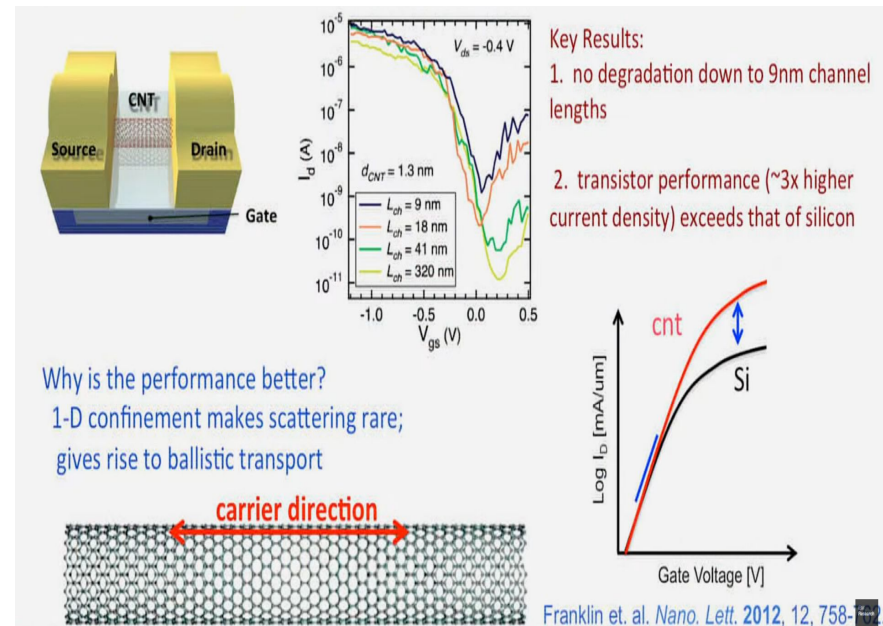
High **Performance-to-Power** ratio compared to that of MOSFETs.

Figure of Merits

Performance comparison FinFET vs CNTFET



Scaling CNTFET

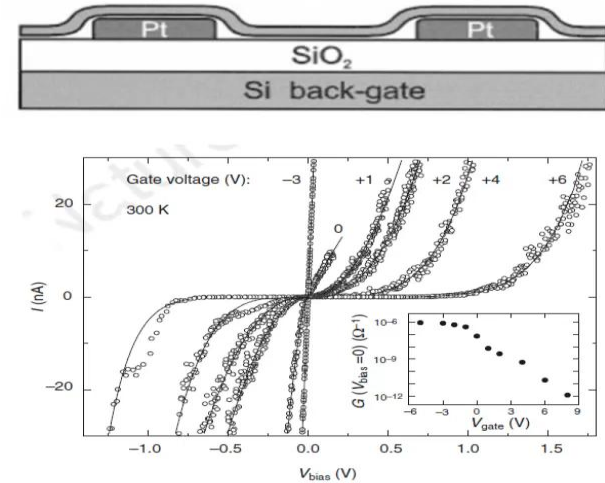


Relevant activities over recent years

(Device Realisation)

Carbon Nanotube Transistors

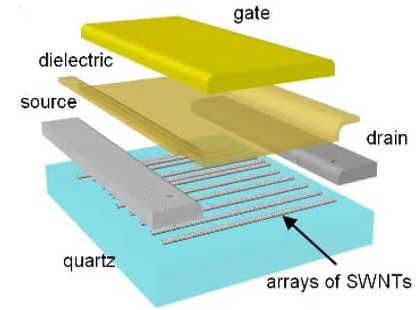
- First ever FET based on CNTs
 - Sander J. Tans, Alwin R. M. Verschuieren & Cees Dekker (1998)
 - Two metal Electrodes
 - Single Wall CNT (SWCNT)
 - Room temperature operation
 - I-V data in accordance with the available semiconductor models of that time



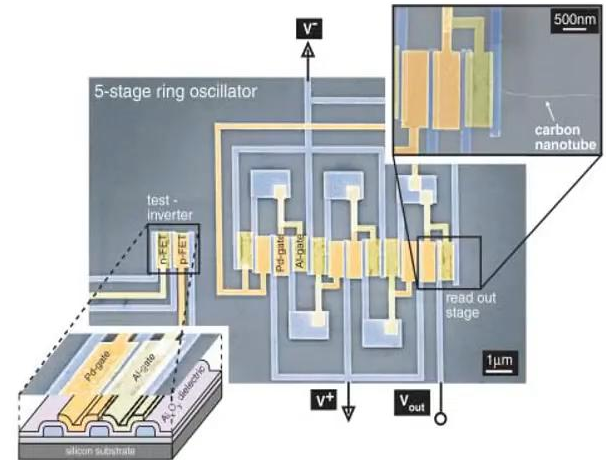
Schematic and I-V curves of first CNTFET [2]

Carbon Nanotube Transistors

- 2001, Single CNTs based **FETs logic circuits** [3]
 - Gain > 10 dB
 - On-off ratio >10⁵
 - Different logic operations
- 2006, Five stage **ring oscillator** on a single CNT [4]
 - 12 FETs
 - Resonances at 13 MHz @ 0.5 V and 52 MHz @ 0.92 V
 - Delay of 1.9 ns per stage
- 2008, Nanotube transistor **radios** [5]
 - SWCNT Audio amplifiers, RF mixers, fixed RF amplifiers and resonant antennas



Schematic of transistor showing SWCNT aligned arrays [5]



Five stage ring oscillator based on a single CNT [4]

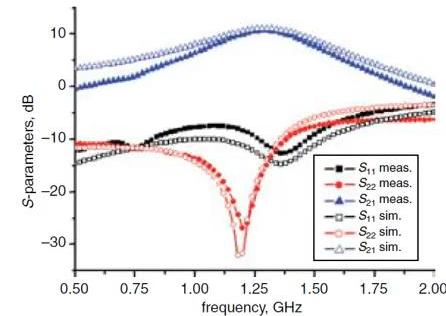
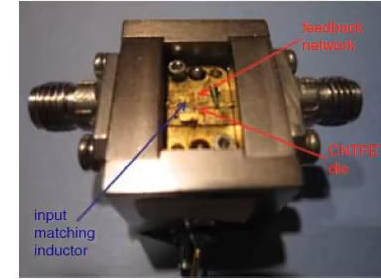
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[5] Kocabas, C., Kim, H., Banks, T., Rogers, J. A., Pesetski, A. A., Baumgardner, J. E., ... Zhang, H. (2008). Radio frequency analog electronics based on carbon nanotube transistors. Proceedings of the National Academy of Sciences, 105(5), 1405-1409. doi:10.1073/pnas.0709734105

Carbon Nanotube Transistors

- **2011**, First CNT based L-band **RF amplifier** [6]
 - Gain > 11 dB @ 1.3 GHz
 - Input/Output return loss < 10 dB
- **2013**, CNT transistor based **computer** [7]
 - Integer sorting and counting at the same time
 - Realization of future electronic systems with high energy efficiency



L band amplifier with S-parameters [6]

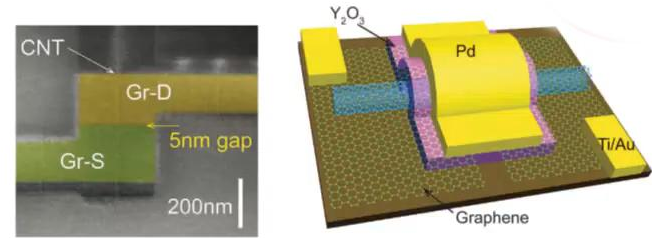
[6] Eron, M., Lin, S., Wang, D., Schroter, M., & Kempf, P. (2011). L-band carbon nanotube transistor amplifier. Electronics Letters, 47(4), 265. doi:10.1049/el.2011.0018

[7] Shulaker, M. M., Hills, G., Patil, N., Wei, H., Chen, H., Wong, H. P., & Mitra, S. (2013). Carbon nanotube computer. Nature, 501(7468), 526-530. doi:10.1038/nature12502

Carbon Nanotube Transistors (Recent achievements)

- 2017, realization of nanotube transistors with 5 nm gate length [8]

- High on-state current
- Large conductance at room temp.
- CNTFET used with graphene contacts
 - Reduction of Drain/Source parasitic capacitances
 - Reduction of short channel effect

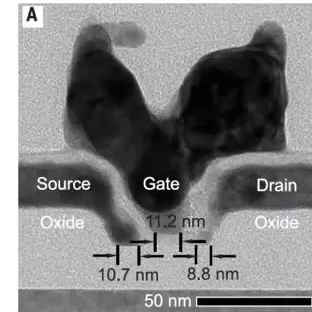


CNTFET with graphene contacts [8]

- 2017, CNT based transistor with 40 nm foot print [9]

- 2017, Fabrication of five stage ring oscillator [10]

- Complimentary carbon nanotubes
- Switching frequency = 2.82 GHz

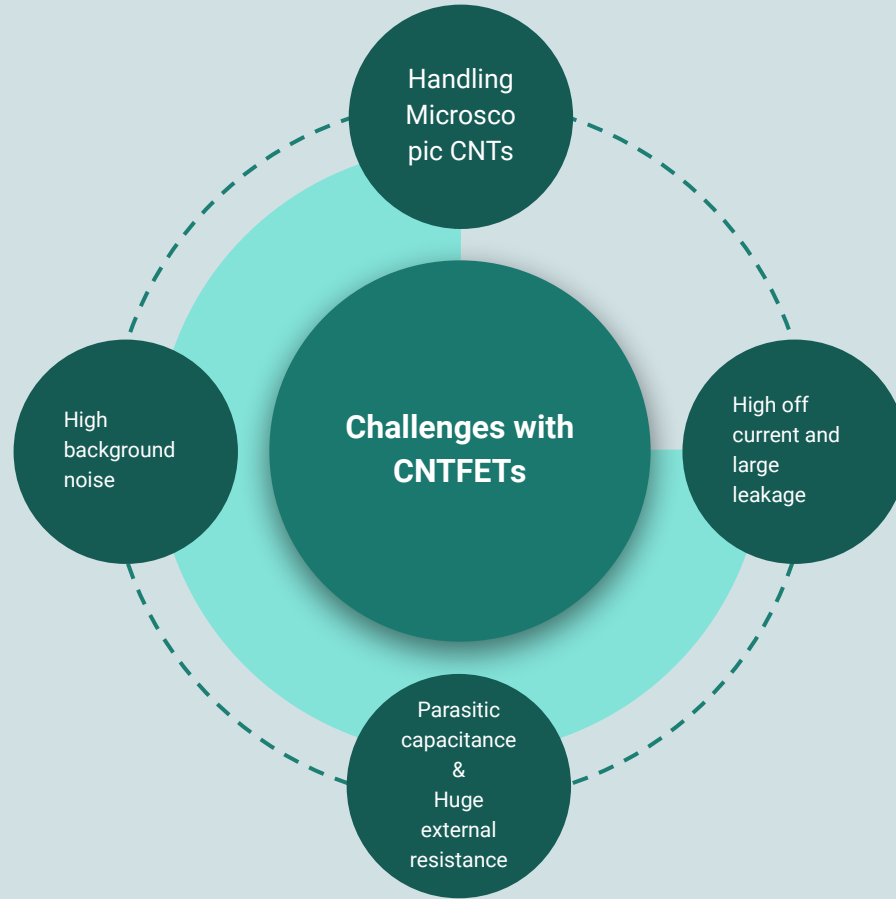


TEM image of single CNT based transistor with 40 nm foot print [9]

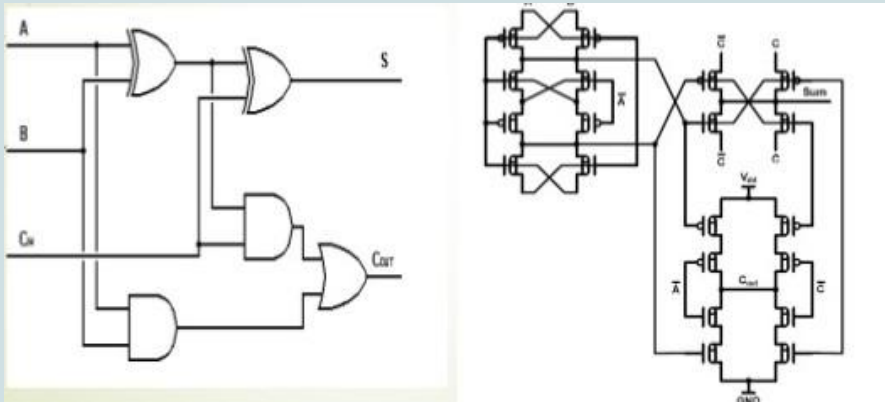
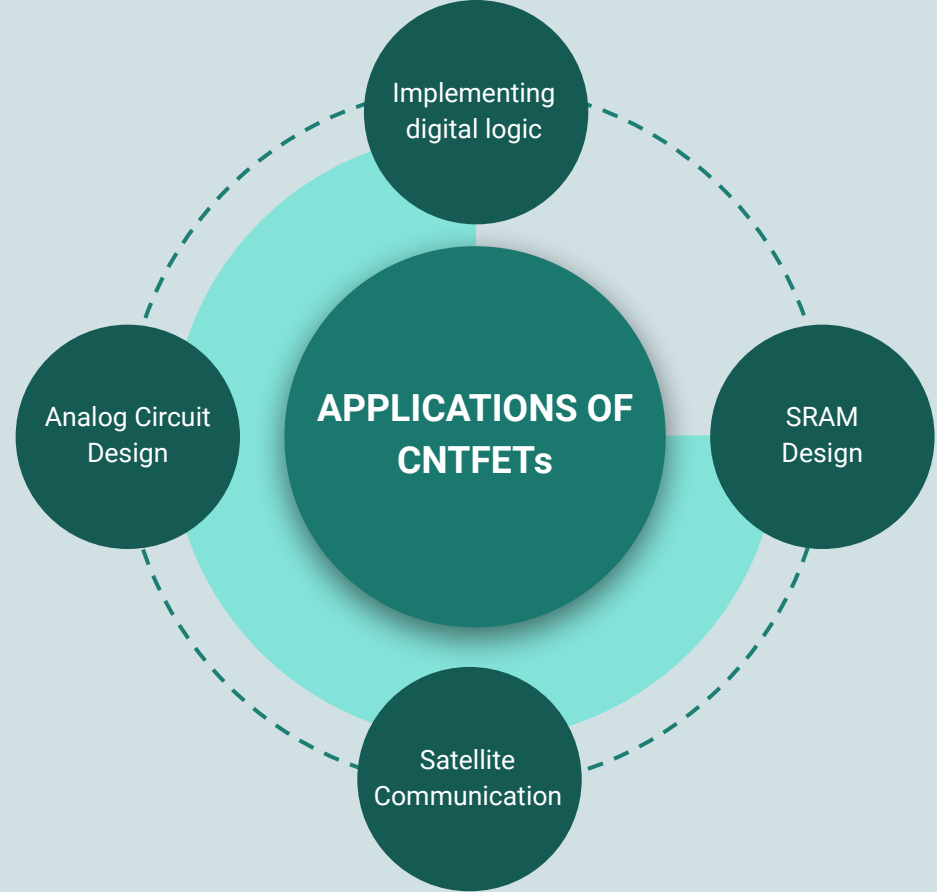
[8] Qiu, C., Zhang, Z., Xiao, M., Yang, Y., Zhong, D., & Peng, L. (2017). Scaling carbon nanotube complementary transistors to 5-nm gate lengths. *Science*, 355(6322), 271-276. doi:10.1126/science.aaj1628

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[10] Han, S., Tang, J., Kumar, B., Falk, A., Farmer, D., Tulevski, G., Haensch, W. (2017). High-speed logic integrated circuits with solution-processed self-assembled carbon nanotubes. *Nature Nanotechnology*. doi:10.1038/nnano.2017.115



CNTFETs can be used in high frequency applications, thanks to the high carrier mobility because of less carrier scattering, as mentioned earlier.



Future Work

The most desirable future work involved in **CNTFETs** will be the transistor with **higher reliability, cheap production cost**, or the one with **more enhanced performances**.

For example, such efforts could be made: adding effects external to the inner CNT transistor like -

- Schottky barrier between the CNT and metal contacts
- multiple CNTs at a single gate
- channel fringe capacitances
- parasitic source/drain resistance
- series resistance due to the scattering effects.

CONCLUSION

- The evolution of carbon nanotube transistors over the last two decades has made CNTFET technology as **potential candidate to replace silicon based CMOS technology**
- CNTFET technology has the capability to go **below 7nm node**
- The high intrinsic carrier mobility and velocity of CNTFETs as well as the thermal ruggedness and their possible high linearity have made CNTFETs also **attractive for high-frequency (HF) applications.**



The image shows four small, clear plastic vials with black caps, arranged in a row on a white surface. The vials contain suspensions of carbon nanotubes. The first vial on the left contains a very dilute suspension, appearing mostly clear with a small amount of dark sediment at the bottom. The second vial contains a slightly more concentrated suspension, showing a light brownish-yellow color. The third vial contains a more concentrated suspension, appearing a darker brownish-yellow. The fourth vial on the right contains the most concentrated suspension, appearing a deep blue-black color. A black arrow points from the text 'trillions of carbon nanotubes' to the bottom of the first vial.

trillions of carbon nanotubes

References

- [1] Rabaey, J.M., Chandrakasan, A. , Nikolic, B., Digital Integrated Circuits Second Edition, 2002, Prentice-Hall
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Q&A